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SERI Photovoltaic Subcontract Reports: 1988 Abstracts and Document Control Information

Photovoltaic Program Branch

June 1990

Prepared under Task No. PV040101

Solar Energy Research Institute

A Division of Midwest Research Institute

1617 Cole Boulevard Golden, Colorado 80401-3393

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PREFACE

This report contains the document control information and abstracts for SERI Photovoltaic (PV) Program Branch publications resulting from SERI's subcontracted PV research. The information is presented for reports published or distributed during fiscal year (FY) 1988. In the past, copies of the subcontractor reports were distributed to a broad spectrum of researchers in the field of photovoltaics at a considerable cost to the program. In an attempt to reduce costs and ensure that all researchers receive those current publications that are of specific interest to them, this report will outline these publications, organized by technology, on a regular basis. A list of additional publications and sources is included herein to provide the photovoltaic community with other sources of information. All of the documents represented here are available from the National Technical Information Service (NTIS) and can be purchased using the NTIS order form at the end of this document. Further information on a given subcontracted program may be obtained from the SERI technical monitor identified on each Document Control Page.

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TABLE OF CONTENTS	
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Amorphous Silicon Program Publications	1
Polycrystalline Thin Film Program Publications	12
High Efficiency Program Publications	23
Additional Publications and Sources	27

Document Control	1. SERI Report No.	2. NTIS Accession No.	3. Recipient's Accession No.
Page	SERI/STR-211-3214	JE88001165	o, hecipients accession to.
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Low-Band-Gap, Amorphous-Silicon-Based Alloys by			February 1988
	opor Deposition, Fina 30 November 1986	1 Subcontract Report,	6. 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
7. Author(s) B.N. Baron, S.S.	. Hegedus, and S. C.	Jackson	8. Performing Organization Rept. No.
9. Performing Organizatio	n Name and Address		10. Project/Task/Work Unit No.
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Golden, Colorado	00401-3333		
5. Supplementary Notes			
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mercury-sensitiz Thin films of a- and 1.0 less that disilane with geto 200°C. Alloy conductivity, eldensity of state	drogenated amorphous ed photochemical value of the state	por deposition using ss than or equal to x were deposited from diluents at substrate ized by measurements time product, sub-bandrogen increased the	loys were deposited by a novel photo-CVD reactor. less than or equal to 1 mixtures of silane and temperatures from 1600 of photo- and dark d-gap absorption, and photovonductivity to 10 ⁻⁵ alloys having a band gap
7. Document Analysis			
a. Descriptors Sili	con solar cells ; amo	orphous state ; thin	films ; chemical
3111	apor deposition	orphous state ; thin	films ; chemical

18. Availability Statement

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National Technical Information Service U.S. Department of Commerce 5285 Port Royal Road Springfield, Virginia 22161

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29

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Document Control	1. SERI Report No. 2. NTIS Accession No.	3. Recipient's Accession No.
Induced Changes Annual Subcontra 1987	SERI/STR-211-3256 DE88001117 f the Origins of Metastable, Lightin Hydrogenated Amorphous Silicon, act Report, 1 February 1986 - 28 February	5. Publication Date October 1987 6.
7. Author(s) J. D. Cohen 9. Performing Organization Department of Ph University of Or Eugene, Oregon	nysics regon	8. Performing Organization Rept. No. 10. Project/Task/Work Unit No. PV740201 11. Contract (C) or Grant (G) No. (C) XB-6-06024-1 (G)
	earch Institute dwest Research Institute vard	13. Type of Report & Period Covered Technical Report 14.
16. Abstract (Limit: 200 wo able changes in t silicon, using a vious studies (us these measurement changes with ligh states between st no qualitative ch	or: Byron Stafford (303) 231-7 rds) This report presents results of an involve he density of deep mobility gap states in variety of junction capacitance technique ing drive-level capacitance profiling) to s, researchers examined how the distribution to soaking and partial annealing through a sates A and B. The results on two phospholange from previous results, which revealed the soaking and partial annealing through a sates A and B. The results on two phospholange from previous results, which revealed the same and the same are successful to the same and the same are successful to	vestigation into the metast- n hydrogenated amorphous es. This work extends pre- o some new samples. With cion of occupied gap states n series of intermediate orus-free samples indicate ed a large metastable in-

ination is not crucial to this increase. Because such an increase is inconsistent with the Si-Si bond-breaking model, this result favors a model in which local configurational changes shift the gap-state energies of existing defects. Transient photocapacitance was applied to undoped films to investigate metastable changes in more detail. Results seemed to confirm the magnitude of the metastable defect creation found by drive-level analysis on the same samples.

17. Document Analysis

- a Descriptors Amorphous state; silicon solar cells; energy losses; doped materials metastable states
- b. Identifiers/Open-Ended Terms
- c. UC Categories 63.

18. Availability Statement	19. No. of Pages
National Technical Information Service U.S. Department of Commerce	30
5285 Port Royal Road Springfield, Virginia 22161	20. Price
	A03

Document Control	1. SERI Report No.	2. NTIS Accession No.	3. Recipient's Accession No.
Page	SERI/STR-211-3288	DE88001151	
4. Title and Subtitle			5. Publication Date
Diagnostics of	Glow Discharges Used	To Produce	February 1988
Hydrogenated Amo		, Annual Subcontract	6.
7. Author(s) A. Gallagher, J.	. Doyle, M. He, G. Li	n, J. Scott	8. Performing Organization Rept. No.
9. Performing Organization	n Name and Address		10. Project/Task/Work Unit No. PV740201
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	search Institute		Technical Report
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15. Supplementary Notes			
1.7	Monitor: W. Luft	(303) 231-182	.3
16. Abstract (Limit: 200 wo			
This report presents results of research done to measure the neutral species produced in silane, silane-hydrogen, disilane, disilane-hydrogen, germane, germane-hydrogen, and silane-germane discharges. Interpretation and modeling of the data in terms of discharge chemistry are also desirable. Mass-spectrometric measurements were made of the stable gases flowing through and produced in silane, disilane, and silane-germane discharges. From these observations, the discharge stoichiometry was determined and the reaction pathways that lead to film deposition clarified. The importance of one processing parameter (power/flow) is explained, and a high ratio of germane/silane depletion in mixed-gas discharges is identified. A calculation of radical deposition in pure silane discharges shows the dominance of SiH3 deposition at low powers and suggests the reason (surface mobility) why this produce good-quality films. Measurements of postdeposition sputtering of a-Si:H films were diagnosed to yield the thickness of the H-rich, growing film surface layer, which is important in understanding and modeling the deposition reactions as well as the effect of ion bombardment on film properties and sputtering. A new, potentially high-rate deposition method was also developed and studied.			
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53

20. Price A04

18. Availability Statement

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U.S. Department of Commerce 5285 Port Royal Road Springfield, Virginia 22161

Document Control 1. SERI Report No. 2. NTIS Accession No.	3. Recipient's Accession No.
Page SERI/STR-211-3231 DE 88001108	
4. Title and Subtitle	5. Publication Date
Research on High-Efficiency, Stacked, Multijunction,	October 1987
Amorphous Silicon Alloy Thin-Film Solar Cells, Final Subcontract Report, 11 October 1983 - 30 October 1986	
7. Author(s) J. Bragagnolo	8. Performing Organization Rept. No.
9. Performing Organization Name and Address	10. Project/Task/Work Unit No.
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Bedford, Massachusetts 01730	11. Contract (C) or Grant (G) No.
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Golden, Colorado 80401-3393	
15. Supplementary Notes	
Technical Monitor: Werner Luft (303) 231-182	
develop high-efficiency, stable, multijunction amorphous It describes new deposition techniques to obtain pinhole by avoiding dust formation in the plasma; the deposition tured SnO, layers by thermal CVD of Sn(CH ₃) ₄ ; a more stati/Ag back contact; the application of the new deposition efficiencies of 10.5%, 10.1%, and 9.4% for a-Si:H p-i-n of a-(Si,Ge):H cells with efficiencies from 5.4% for a-(graded-bandgap cells; and the development of a-Si/a-(Si, and 7.2% efficiencies.	-free, a-Si:H alloy films of low-absorptance, tex- ble, high-reflectance n techniques to achieve devices; the development Si,Ge):H cells to 7.5% for
a Descriptors Amorphous state ; silicon solar cells ; chemi	cal vapor deposition ;
b. Identifiers/Open-Ended Terms	
c. UC Categories 63	
18. Availability Statement	19. No. of Pages
National Technical Information Service	123
U.S. Department of Commerce	1 · · · · · · · · · · · · · · · · · · ·
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Springfield, Virginia 22161	20. Price
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Form No. 0069 (6-30-87)

Document Control Page	1. SERI Report No. SERI/STR-211-3332	2. NTIS Accession No. DE 8800 175		
4. Title and Subtitle		1,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	5. Publication Date	
Optimization of Transparent and Reflecting Electrodes for Amorphous Silicon Solar Cells, Final Subcontract Report, 1 October 1986 31 November 1987				
7. Author(s) R. G. Gordon et	al.		8. Performing Organization Rept. No.	
9. Performing Organization	Name and Address		10. Project/Task/Work Unit No.	
Department of Ch Harvard Univers Cambridge, Massa			11. Contract (C) or Grant (G) No. (C) XB-7-06110-1 (G)	
12. Sponsoring Organization Solar Energy Res	earch Institute		13. Type of Report & Period Covered Technical Report	
1617 Cole Boulev Golden, Colorado			14.	
15. Supplementary Notes	landana 1 Ohi Ca	\ \ -		
SERI Technical Monitor: J. Ohi (303) 231-7681				
In this research, hydrogenated amorphous silicon (a-Si:H) films were deposited by an inexpensive, thermally induced, atmospheric-pressure chemical vapor deposition (CVD) process. High-quality films were grown at 300 Å/s, more than two orders of magnitude faster than those produced by conventional glow discharge. Sources of uncontrolled oxygen, boron, phosphorus, and carbon contamination were identified and eliminated. The efficiency of a-Si solar cells can be increased by using rough, rather than smooth, tin oxide as the front-surface transparent electrode, because the rough tin oxide-silicon interface increases the absorption of red light (light trapping) and reduces the reflection loss of light across the whole spectrum. We produced, by CVD, rough tin oxide films from tetramethyltin. Cells grown on the rough films had higher efficiencies than those grown on smooth tin oxide. We also used a precursor tin compound (dimethyltin dichloride) that is less costly and less hazardous than some others. Rough films can be grown from dimethyltin dichloride more than three times faster than from tetramethyltin. To combine the CVD processes, we need a layer that prevents the tin oxide layer from being attacked by the silicon, such as a barrier layer of titanium oxide, which seems to be effective.				
17. Document Analysis	· · · · · · · · · · · · · · · · · · ·			
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72

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271

18. Availability Statement

5285 Port Royal Road

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National Technical Information Service U.S. Department of Commerce

Document Control Page	1. SERI Report No. SERI/STR-211-3343	2. NTIS Accession No. DE88001176	3. Recipient's Accession No.	
4. Title and Subtitle			5. Publication Date	
Research on High-Efficiency, Single-Junction, Monolithic, Thin-Film Amorphous Silicon Solar Cells, Semiannual Subcontract Report No. 3, 1 Dec. 1985-31 May 1986			June 1988 6.	
7. Author(s) F.E. Aspen et al			8. Performing Organization Rept. No.	
	n Name and Address nformation Sector Lat	oratories	10. Project/Task/Work Unit No.	
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15. Supplementary Notes				
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16. Abstract (Limit: 200 wo	rds)			
lithic, thin-film	n amorphous silicon s	olar cells. The work	ency, single-junction, mono- k was divided into five aductor materials; web	

This report describes progress in research on high-efficiency, single-junction, monolithic, thin-film amorphous silicon solar cells. The work was divided into five tasks, wich include research on a-Si materials; nonsemiconductor materials; web growth; and monolithic, intraconnected cells and submodules. Also described is work done with a multichamber deposition system. Results included achieving an optical band gap of 1.73-1.75 eV in the intrinsic i-layer, A new roll coater was acquired for use as a multilayer transparent top-contact deposition system. Textured substrates were also investigated to increase the short-circuit current. In doping profile work, a model indicated that a carbon profile could be used in place of the boron profile to raise the open-circuit voltage. Silver-filled epoxy-ITO contacts were found to be unstable over time. Two web-growth methods were demonstrated to obtain submodule performance that is about 80% of small-area (1 cm²) efficiency. With the multichamber deposition system, a-Si p-i-n layers were deposited onto metallized polyimide web in a continuous, roll-to-roll process.

17. Document Analysis

- a. Descriptors Photovoltaic cells; amorphous state; silicon solar cells; thin films; deposition; doped materials
- b. Identifiers/Open-Ended Terms
- c. UC Categories

271

18. Availability Statement	19. No. of Pages
National Technical Information Service	65
U.S. Department of Commerce	
5285 Port Royal Road Springfield, Virginia 22161	20. Price
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Document Control Page	1. SERI Report No. SERI/STR-211-3350	2. NTIS Accession No. DE 88001169	3. Recipient's Accession No.
4. Title and Subtitle		10000001101	5. Publication Date
Research on Amorphous-Silicon-Based Thin-Film Photovoltaic Devices, Semiannual Subcontract Report, 1 July 198731 December 1987		May 1988	
		contract Report,	6.
7. Author(s) W. Bottenberg, k	K. Mitchell, and R. W	ieting	8. Performing Organization Rept. No.
9. Performing Organization	n Name and Address		10. Project/Task/Work Unit No.
ARCO Solar, Inc.			PV840201
Camarillo, Calif	fornia 93010		11. Contract (C) or Grant (G) No.
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Goden, Colorado	80401-3393		
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16. Abstract (Limit: 200 wo	rds)		·
four-terminal hy indium-diselenid silicon-hydrogen TFS devices and rear transparent also fabricated; understood. Repwere fabricated circuits was low Efficiencies obt	brid tandem submodul (c(CIS)-based bottom (TFS)-based top cir submodules were fabr conductors. High-p however, the locat presentative four-teri from TFS and CIS com per than expected, be	es. The module design circuit and a semitrouit and a semitrouit. High-performanicated in which ZnO werformance CIS devices ion and nature of the minal hybrid tandem openent circuits. Opticause of reflection loces and modules inclu	was used in the front and es and submodules were e junction are not yet devices and submodules cical coupling between the losses at key interfaces.
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20. Price A06

Form No. 0069 (6-30-87)

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5285 Port Royal Road Springfield, Virginia 22161

National Technical Information Service

Document Control	1. SERI Report No.	2. NTIS Accession No.	3. Recipient's Accession No.	
Page	SERI/STR-211-3351	DE88001168		
4. Title and Subtitle		5. Publication Date		
Research of Amor	ohous Silicon-German	ium Alloys for Tandem	May 1988	
	ual Subcontract Repo		6.	
7. Author(s) W. Paul and K.D.	Mackenzie		8. Performing Organization Rept. No.	
9. Performing Organizatio	n Name and Address		10. Project/Task/Work Unit No.	
Division of Appl	ied Sciences		PV840201	
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15. Supplementary Notes		-)		
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16. Abstract (Limit: 200 words)				
produce amorphou electronic prope understand why ta-Sil-xGex:H, wh remain unchanged and on the micro scopy, gas evolu with a high Ge c vapor deposition ing photoelectro and it is theref the interface of	s Si-Ge alloys with rties will be compar he photoconductivity ile most of the comm. The focus of this structure of the filtion, and differentiontent. Films were in a new type of ap nic properties, depeore important to und	a band gap near 1.3 to able to those of a-Si of a-Si _{1-x} Ge _x :H:F is only measured optical investigation was on ms as revealed by tranal scanning calorimetrade both by glow disciparatus. Structure, work on the totality of erstand the conditions hen SiH ₄ , GeH ₄ , and H ₂	onditions necessary to 1.4 eV whose photo- H. It is essential to superior to that of and electronic properties deposition conditions asmission electron micro- ry, concentrating on alloys charge and by photochemical very important in determin- f the deposition parameters, in the plasma and at are present in different	
	ovoltaic cells ; amo nergy gap ; depositi	rphous state ; silicom	n solar cells ;	
b. Identifiers/Open-Ended Terms				

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5285 Port Royal Road
Springfield, Virginia 22161

19. No. of Pages

69

A04

20. Price

c. UC Categories 271

18. Availability Statement

Document Control Page	1. SERI Report No. SERI/STR-211-3352	2. NTIS Accession No. DE 88701167	3. Recipient's Accession No.	
4. Title and Subtitle	morphous Silicon Allo		5. Publication Date May 1988	
	port, 15 January 1987		6.	
7. Author(s) R. E. Norberg a	and P. A. Fedders		8. Performing Organization Rept. No.	
9. Performing Organizatio			10. Project/Task/Work Unit No.	
Department of P	Physics		PV840201	
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15. Supplementary Notes				
· ·	Monitor: W. Luft ((303) 231-18	23	
16. Abstract (Limit: 200 words)				
The principal objective of the first year of this research program was to improve our understanding at the microscopic level of amorphous silicon-germanium alloy films deposited under various conditions to assist researchers in producing higher quality films. The method was a joint theoretical and experimental approach to the correlation of muclear magnetic resonance (NMR), electron spin resonance (ESR), and other characterizations, especially relating to rearrangements of hydrogen. Deuteron magnetic resonance reveals the presence of (and changes in) tightly bonded hydrogen (deuterium), weakly bonded hydrogen, molecular hydrogen, and rotating silyl groups. Ge-D configurations appear to be more varied than Si-D. It has been shown that ESR hyperfine structure results can be interpreted very well via dangling bonds, but not with floating bonds. The presence of fluorine correlates with the occurrence of larger microvoid dimensions.				
17. Document Analysis				
a. Descriptors Photov	voltaic cells ; amorp	phous state ; silicon	solar cells ;	
	semiconductor materials ; fluoride ; germanium ; laboratory b. Identifiers/Open-Ended Terms equipment ; nuclear magnetic resonance			

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Form No. 0069 (6-30-87)

c. UC Categories 271

18. Availability Statement

National Technical Information Service

U.S. Department of Commerce 5285 Port Royal Road

9

19. No. of Pages

35

20. Price

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Document Control Page	1. SERI Report No. SERI/STR-211-3353	2. NTIS Accession No.	3. Recipient's Accession No.	
4. Title and Subtitle			5. Publication Date	
Amorphous Silicon Photovoltaic Devices Prepared by			June 1988	
	tochemical Vapor Depo		6.	
Order Silanes, A	nnual Subcontract Rep	ort, 1 September		
1986 31 Augus	† 1987	<u> </u>		
7. Author(s)			8. Performing Organization Rept. No.	
A.E. Delahoy and	H F Schade			
9. Performing Organizatio			10. Project/Task/Work Unit No.	
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15. Supplementary Notes				
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16. Abstract (Limit: 200 wo	ords)			
The common day			:	
			igh-efficiency photovoltaic	
devices by photo	ochemical vapor depos	ition of higher order	r silanes. The photostabil-	
ity of these devices was compared to that of devices produced by the glow-discharge				
technique. Hydrogenated amorphous silicon cell efficiencies of at least 7.5% were				
obtained using p-i-n structures and aluminum back contacts. Using silver contacts				
increased the efficiency to about 8%. After 6 minutes of light soaking, there was				
no significant difference between the photostabilities of these cells and those produced by glow discharge. The efficiencies might be increased further if some				
produced by glow	w discharge. The eff	iciencies might be ir	ncreased further if some	
remaining proble	ems can be addressed,	such as by using a d	different substrate	
preparation method or a higher pumping speed at the deposition chamber.				
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17. Document Analysis				
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271				
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5285 Port Royal				
Springfield, Vir	rginia 22161		20. Price	
			A03	

Document Control	1. SERI Report No.	2. NTIS Accession No.	3. Recipient's Accession No.
Page SERI/STR-211-3354 DE88001[9] 4. Title and Subtitle Preparation and Properties of High-Deposition-Rate a-Si:H Films and Solar Cells Using Disilanes, Annual Subcontract Report, 1 May 198730 April 1988			5. Publication Date June 1988 6.
7. Author(s) P.K. Bhat, H. Chatham, and A. Madan			8. Performing Organization Rept. No.
9. Performing Organization Glasstech Solar Wheatridge, Colo	Inc.		10. Project/Task/Work Unit No. 11. Contract (C) or Grant (G) No. (C) ZB-7-06002-1 (G)
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SERI Technical Monitor: W. Luft (303) 231-1823 16. Abstract (Limit: 200 words)

15. Supplementary Notes

This report contains results of the first year of research on producing p-i-n amorphous silicon solar cells with the intrinsic layer deposited from higher order silanes at deposition rates of 1 nm/s or more. The research was divided into three major areas: (1) diagnostic studies of monosilane and disilane RF discharges using optical emission spectroscopy and mass spectrometry to assist in optimizing discharge conditions and gas-phase processes; (2) parametric studies of material properties of i-layers prepared from disilane as a function of deposition rate and other process parameters; and (3) parametric studies of p-i-n devices with the i-layer prepared from disilane at various deposition rates. The focus during the first year was to fabricate a p-i-n solar cell with 9% AM1.5 efficiency over an area greater than 0.08 cm² with the i-layer deposited at 1 nm/s or more. Material

properties such as the dark and AM1.5 light conductivities, optical band gap, and conductivity activation energy showed a weak dependence on deposition rate. The performance characteristics of unoptimized p-i-n solar cells with i-layers prepared from disilane were independent of the deposition rate of the i-layer. A p-i-n device was prepared at a rate close to 1 nm/s with an AM1.5 efficiency of 9%.

17. Document Analysis

a. Descriptors

Photovoltaic cells; silicon solar cells; amorphous state; deposition

b. Identifiers/Open-Ended Terms

c. UC Categories 271

18. Availability Statement

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CuInSe, Solar Cell Research by Sputter Deposition,	June 1987
Annual ² Subcontract Report, 1 January 1986 -	6.
31 December 1986	
7. Author(s)	8. Performing Organization Rept. No.
J. A. Thornton, T. C. Lommasson, and H. Talieh 9. Performing Organization Name and Address	10. Project/Task/Work Unit No.
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University of Illinois	11. Contract (C) or Grant (G) No.
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Golden, Colorado 80401-3393	
15. Supplementary Notes	
Technical Monitor: H. S. Ullal (303) 231-1841	
16. Abstract (Limit: 200 words) This report contains results of resea	irch on CulnSe, solar cells
by sputter deposition. Most of the CuInSe ₂ /CdS devices deposited by reactive sputtering have been ² characterize	ad by relatively low one
circuit voltages. Typical values range from 0.22 to 0.	
factor may be the lower In composition in the top layer	of composite two-laver
CuInSe, films (Cu-rich base layer, In-rich top layer) t	
cation. The reason for the lower In content is an In r	
during deposition at elevated temperatures. Therefore,	
this work was to increase the In content in the top lay	ver of CuInSe ₂ films
deposited in composite two-layer configurations on Mo-c	coated, glass substrates.
Variations in the relative currents to the Cu and In sp H ₂ Se injection rate, and the substrate temperature were	outtering sources, the
decrease from 450° to 400°C increased the In composition	on from 25 at % to about
27 at. %. A second approach, in which the In sputterin	ng source was operated for
a short time with no Cu sputtering, also yielded promis	
17. Document Analysis	
a Descriptors Photovoltaic cells; copper selenide solar o	ells : denosition : thin
films	errs, acposition, cirin
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b. Identifiers/Open-Ended Terms	
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4. Title and Subtitle Preparation and Properties of Evapor Final Subcontract Report, 16 Februar 31 March 1987	5. Publication Date July 1987 6.	
7. Author(s) R.H. Bube, A.L. Fahrenbruch, K.F. Ch	nien	8. Performing Organization Rept. No.
9. Performing Organization Name and Address Department of Materials Science and Engineering Stanford University Stanford, California 94305		10. Project/Task/Work Unit No. 3494.10 11. Contract (C) or Grant (G) No. (C) XL-4-04022-1 (G)
12. Sponsoring Organization Name and Address Solar Energy Research Institute 1617 Cole Boulevard Golden, Colorado 80401		13. Type of Report & Period Covered Technical Report 14.
15. Supplementary Notes SERI Technical Monitor: Richard Mit	chell	
Previous work on evaporated CdTe fil to successful p-type doping of CdTe of the films in various ambients the were done in Te, Cd, P, and As vapor showed large effects on series resistance values of In/p-CdTe/graph decrease was due to a decrease in graph height, and thus was due to large in not altered substantially. Although	during deposition. Is was examined as a Is and in vacuum, ai Itance and diode par Ite structures decreain boundary and/or Icreases in mobility	Post-deposition annealing a means of doping. Anneals ir, and Ar, all of which rameters. With As, series reased markedly. This back contact barrier v; the carrier density was

17. Document Analysis

a. Descriptors

Photovoltaic cells; thin films; cadmium telluride solar cells; deposition

substantial, the diode characteristics became worse. The decreases were not observed when CdS/CdTe cells were fabricated on Te vapor-annealed films. Preparation of ZnO films by reactive evaporation yielded promising results. Deposition of p-ZnTe films by hot-wall vapor evaporation, using conventional

techniques, yielded acceptable films without intentional doping.

b. Identifiers/Open-Ended Terms

c. UC Categories 63

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15. Supplementary Notes	#	the second of the second				
Technical Monito	r: H. S. Ullal (3	<u>03) 231-1841 </u>				
16. Abstract (Limit: 200 wo	rds)					
Several aspects	of the impact of Cul	nSe nolvervstallini	ty on solar cell perform	ance		
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			of CuInSe ₂ layers and			
completed cells	show large variation	completed cells show large variations in both the magnitude and angular distribution				
of scattered lig	ht. Localized illum		ial variations in photo-	.]		
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7. Author(s) P.K. Ajmera and I	H.Y. Shin		8. Performing Organization Rept. No.
9. Performing Organization Name and Address Department of Electrical and Computer Engineering			10. Project/Task/Work Unit No. PV840601
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15. Supplementary Notes

SERI Technical Monitor: R. Mitchell

16. Abstract (Limit: 200 words)

This research involved the vacuum deposition of thin films of $ZnSnP_2$. This ternary chalcopyrite semiconductor has a direct energy gap of 1.66 eV. Its constituent elements, zinc and phosphorus, are plentiful in the U.S. and tin is readily available from abroad. This makes $ZnSnP_2$ an attractive material for low-cost terrestrial photovoltaic applications. Growth conditions were experimentally determined to obtain near-stoichiometric vacuum growth of thin films of $ZnSnP_2$ on GaAs, quartz, and molybdenum substrates utilizing elemental sources. The grown films were characterized by chemical, electrical, and optical measurements and by morphological studies. Attempts were made to fabricate simple heterostructure devices on the grown layers. This research provides information on the relevant properties of vacuum-grown thin films of $ZnSnP_2$ for its potential application in polycrystalline thin-film PV devices.

17. Document Analysis

- a. Descriptors Photovoltaic cells; thin films; semiconductor materials; deposition
- b. Identifiers/Open-Ended Terms

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CdZnTe as a Wide-Band-Gap Absorber for a Tandem, Thin-			October 1987
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31 August 1987			
7. Author(s) K. R. Zanio			8. Performing Organization Rept. No.
9. Performing Organization Name and Address Ford Aerospace and Communications Corporation		10. Project/Task/Work Unit No. PV740601	
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	ort, 15 February 1985	•	6.
7. Author(s) D. E. Schafer			8. Performing Organization Rept. No.
9. Performing Organization	n Name and Address		10. Project/Task/Work Unit No.
Honeywell Physi	cal Sciences Center		PV740601
Bloomington, Mi	nnesota 55420		11. Contract (C) or Grant (G) No.
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SERI Technical	Monitor: R. Mitchell		
-	marizes the applicati		c chemical vapor deposition

This report summarizes the application of metal-organic chemical vapor deposition (MOCVD) film growth to two aspects of CdTe/ITO solar cell fabrication: (1) the growth of large-area CdTe films on ITO, and (2) the formation of low-resistance ohmic contacts to p-type CdTe. A reduced-temperature MOCVD process was developed for the deposition of CdTe films in order to minimize the potential for chemical and physical changes in the ITO layer during cell fabrication. MOCVD growth of HgTe and ZnTe were developed for fabrication of ohmic contacts (opaque and long-wavelength transparent, respectively) to the CdTe layer of the photovoltaic structure. This report details the MOCVD reactor geometries and process parameters used in the development of the CdTe, HgTe, and ZnTe layer growth, as well as the results of C-V analysis of the carrier concentration in the MOCVD CdTe layers and resistance characteristics of various interfaces formed by CdTe, HgTe, and ZnTe.

17. Document Analysis

- a. Descriptors Photovoltaic cells; cadmium telluride solar cells; thin films; chemical vapor deposition
- b. Identifiers/Open-Ended Terms
- c. UC Categories 273

18. Availability Statement	19. No. of Pages
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Document Control 1. SERI Report No. 2. NTIS Accession No. SERI/STR-211-3229 DE 85 00118 3	3. Recipient's Accession No.
4. Title and Subtitle	5. Publication Date
Thin-Film Cadmium Telluride Solar Cells, Annual	October 1987
Subcontract Report, 1 May 1986-31 May 1987	6.
7. Author(s)	8. Performing Organization Rept. No.
T. L. Chue	
9. Performing Organization Name and Address Southern Methodist University	10. Project/Task/Work Unit No. 3494 . 10
Dallas, Texas 75275	11. Contract (C) or Grant (G) No.
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15. Supplementary Notes	
SERI Technical Monitor: H.S. Ullal (303) 231-189	
16. Abstract (Limit: 200 words)	
Cadmium telluride, with a room-temperature band-gap ener	gv of 1.5 eV. is a
promising thin-film photovoltaic material. The major ob	
has been to demonstrate thin-film CdTe heterojunction so	
area greater than 1 cm² and photovoltaic efficiencies of	
p-CdTe/CdS/SnO ₂ :F/glass solar cells with an AM1.5 effici	
reported previously. This report contains results of wo	
deposition, resistivity control, and characterization of	
close-spaced sublimation process; (2) the deposition of materials; (3) the electrical properties of CdS/CdTe het	
formation of stable, reproducible, ohmic contacts (such a	
and (5) the preparation and evaluation of heterojunction	
17. Document Analysis	<u>and the control of t</u>
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	Copper Ternary Hetero		November 1987
	Subcontract Report, 1	October 1984-	6.
31 May 1987			
7. Author(s) W. E. Devaney. et			8. Performing Organization Rept. No.
9. Performing Organization			10. Project/Task/Work Unit No.
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based thin-film p incorporating Ga characterized. C of Ga contents an Ga content. A 10 American Society Ga fraction of 0. monolithically in with 9.5% total a assisted depositi source, indium-ti an E-gun evaporat variations with s for the CuInSe ₂ /C CuInSe ₂ /CdZnS cel	olycrystalline heter fractions (x in CuIn uInGaSe,/CdZnS heter d show the expected .2% efficiency (Sola for Testing and Mate 23, the highest effiterconnected four-ce rea efficiency (SERI on of the selenide an oxide reactive spuion source. Spectra elenide composition dZnS devices. The	cojunction solar cells at Ga Se ₂) from 0.04 cojunction devices were variations in V and ar Energy Research Institute (ASTM) 87) was aciency reported. A Cell series string 91 cell series string 91 cell series string 91 cell series at a new destater deposition, and all response and current before and after heat aighest AMI total area ag test, AMI spectrum)	to 1.0 were prepared and re fabricated for a range spectral response with stitute (SERI) test, measured for a cell with CuInSe CdZnS are in area was fabricated alts are presented on ionsign for the Se evaporation CdZnS films prepared from at-voltage characteristic treatment are discussed
a. Descriptors Photo	osition	films ; copper selen	aide solar cells ;
c. UC Categories 63			
18. Availability Statement			19. No. of Pages
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Stable, High-Efficiency, CuInSe ₂ -Based, Polycrystalline			October 1987
Thin-Film Tande	em Solar Cells, Final		6.
16 March 1984	- 15 March 1987		
7. Author(s) R. W. Birkmire	and J. E. Phillips		8. Performing Organization Rept. No.
9. Performing Organization			10. Project/Task/Work Unit No. PV740301
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15. Supplementary Notes			
Technical Monit	tor: Richard Mitchel	1 (303) 231-1	379 ch was to obtain a stable,
transparent contaconducting oxides were made with efficulnSe /(CdZn)S cation using Knudsover 10%. The corange and still ythe V of the derecombination. It is to change carritrolled by band-tobeen made with efficiency contacts of the been made with efficiency contacts of the description of the descr	acts. A suitable cons (ITO and SnO ₂) in conficiencies over 8.5% cells was developed beneation sour omposition of the Culyield high-efficiency evices; analysis show the effect of oxidizing rier concentration and to-band recombination	tacting system was de injunction with a thin . A reproducible fab ased on CuInSe, films rces. These cells wenSe, films can be var cells. Adding Zn to ed that the V is nong and reducing heat d thus V Analysis. Monolithic tandem	elop a CdTe cell with eveloped using transparent layer of copper. Cells prication process for grown by vacuum evaporter made with efficiencies ried over a considerable the CdS did not increase at controlled by interface treatments on CuInSe, cells suggests that J is con-CuInSe, CdTe cells have sibility of this approach.
17. Document Analysis a. Descriptors			
Photovoltaic	cells ; copper selen	ide solar cells ; thi	n films; efficiency
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Document Control Page	1. SERI Report No. SERI/STR-211-3289	2. NTIS Accession No. DE 88 00 1 60	3. Recipient's Accession No.
 Title and Subtitle Ternary Adamanti 	ine Materials for Low	-Cost Solar Cells,	5. Publication Date February 1988
Final Subcontract 1986	et Report, 1 November	1984-31 December	6.
7. Author(s) D. Cahen and G.	Hodes		8. Performing Organization Rept. No.
9. Performing Organization	n Name and Address		10. Project/Task/Work Unit No.
Weizmann Institu	ite of Science		PV740301
Rehovot, Israel			11. Contract (C) or Grant (G) No.
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15. Supplementary Notes		* .	

SERI Technical Monitor: H. S. Ullal (303) 231-1841

16. Abstract (Limit; 200 words)

Several methods were investigated to prepare CuInS(e)2, using electroplating techniques near room temperature, to explore them for obtaining photovoltaically active films. No significant photoactivity resulted, unless an annealing step (at greater than or equal to 400°C) was added to the process. Promising PV activity was found only if this anneal was carried out in a S(e)-containing atmosphere. Therefore, in part of this project, the two steps, metal deposition and chalcogen incorporation, were separated. These experiments showed that chalcogenization is the most critical step in obtaining films that are PV active. The composition of the films obtained after the chalcogenization step can be varied considerably by a chemical, postannealing treatment. PV activity of films was checked in a simple, rapid way by sputtering Cd onto them. Both these junctions, as well as those obtained by ITO deposition, show improved rectification and PV activity, after air anneal of the chalcogenized film, before junction formation. Possible causes for this are discussed. Separate C-V experiments on Al/CuInSe₂/Mo structures, using CuInSe2/Mo films, provided direct evidence of the persistence of two types of CuInSe, layers, distinquishable by their doping concentration.

17. Document Analysis

- a. Descriptors Photovoltaic cells; thin films; copper indium diselenide solar cells; chalcogenides; annealing
- b. Identifiers/Open-Ended Terms
- c. UC Categories 273

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	ium Telluride Solar (port, 1 May 198531	Cells, Final	5. Publication Date June 1988 6.
7. Author(s) T. L. Chu			8. Performing Organization Rept. No.
9. Performing Organization			10. Project/Task/Work Unit No.
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15. Supplementary Notes SERI Technical	Monitor: H. S. Ulla	11 - (303) 231	<u>- 1841</u>
resistivity con of the elements deposition and deposition of properties of (heterojunction	ntrol, and characteris (CVE) and close-spa characterization of p-HgTe as a low-resis CdS/CdTe heterojuncti solar cells. CdS/Cd	ization of p-CdTe fill aced sublimation (CSS transparent conducti stance ohmic contact ons; and (5) the pre TTE solar cells showe	ed to (1) the deposition, ms by combining the vapor) techniques; (2) the ng semiconductors: (3) the to p-CdTe; (4) the electrical paration and evaluation of d the best photovoltaic iciency of about 10.6%.
17. Document Analysis a. Descriptors Photo b. Identifiers/Open-E c. UC Categories 273	heterojunctions	nium telluride solar	cells; thin films;
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4. Title and Subtitle			5. Publication Date
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Final Subcontra	ict Report, April 198	4 - April 1986 🗼 📙	July 1987
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7. Author(s)		ļ	8. Performing Organization Rept. No.
i	S. P. Tobin, and R. G	Wolfson	
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15. Supplementary Notes			
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16. Abstract (Limit: 200 wo			
emphasizing hete crystal silicon a new metal-orga GaAlAs, and GaAs optimization of a understanding of described. The development of a GaAsP cell and a efficient GaAs-o	eroepitaxial growth o wafer. The report d anic vapor deposition sP on 2-indiameter the growth of Ge fil 9% efficient GaAs-on f the GaAs-on-Si grow work also included p a GaAsP-on-GaAs growt a 17.7% efficient GaA on-GaAs cell. Also d	f a III-V compound matescribes the start-up (MOCVD) reactor for substrates with excel ms on Si by a simple Ge-on-Si solar cell. th process and in the roduction of a 7% eff h technology; product As cell on GaAs; and	and characterization of the growth of GaAs, lent uniformity; CVD technique; and The advancements in the quality of the films are icient GaAs-on-Si cell; ion of a 16.5% efficient production of a 20.8% ents in cell processing
17. Document Analysis			
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4. Title and Subtitle			5. Publication Date July 1987
	tibandgap Solar Cel 1984 - 31 January	ls, Final Subcontract 1987	
7. Author(s) J.A. Cape, L.M.	Fraas, P.S. McLeod	, L.D. Partain	8. Performing Organization Rept. No.
9. Performing Organization			10. Project/Task/Work Unit No.
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16. Abstract (Limit: 200 wo	rds)		
attempted to undependable, and traced to the and traced to the and were also made to GaAsP and GaAsSI lead to higher on optimizing vali-V ratios, checking lattice impurities; and	derstand the effects these structures. The material impurition of efforts were madersine (predominantly to purify these. We and on developing efficiencies. In deacuum chemical epital mamber designs, etce-mismatch effects;	s of lattice mismatch Severe unreproducibilities. CP ₂ Mg, the p-dopare to purify it. Impury water vapor) and the ork focused on optimize the growth process. eveloping component carry growth conditions.); on developing cell	ity was encountered and nt, was found to be rity effects were also e gallium alkyls. Efforts zing component cells of This, though, did not ells, work was also done (temperatures, flow rates, I transition layers and ocessing; on reducing
17. Document Analysis a. Descriptors Photo	voltaic cells ; gal	lium arsenide solar ce	ells ; efficiency ;
	oped materials ; ep		
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4. Title and Subtitle			5. Publication Date October 1987
	gle-Crystal CdTe Sola	. •	
Final Subconti 1 February 198	ract Report, 1 Februa 37	ry 1985-	6.
7. Author(s) J. M. Borrego,	S. K. Ghandhi		8. Performing Organization Rept. No.
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16. Abstract (Limit: 200 wo acterization of efficiency sola by organometall FWHM of 5.8 meV sically doped b level achieved for the first t the n-type mate energy level, a to identify the were produced or of GaAs so this	single-crystal CdTe r cells. It was demo ic vapor phase epitax, the lowest value fo oth n- and p-type wit for p-type is the hig ime in an OMVPE systerial, five deep level nd concentration were ir defect character. In these layers. The is a potentially sup	es two years of work layers, to explore the nstrated that high-quy (OMVPE), whose photer them yet achieved. In them yet achieved in the set yet reported in the set yet reported in the determined. A thermodetermined and podiode characteristics erior material for so	on the growth and char- neir potential for high- nality layers can be grown columinescence peak has a CdTe layers were extrin- , respectively. The doping the literature, achieved of 2.0 mm was measured. In r capture cross section, odynamic analysis was made n junction devices were superior to those plar cells.
a. Descriptors Photo	ovoltaic cells ; cadm rials ; Schottky barr		ells ; semiconductor
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ADDITIONAL PUBLICATIONS AND SOURCES

The following publications were produced under the DOE Photovoltaics Program or are widely available publications in which substantial DOE-supported work is reported. Those that and are available from the National Technical Information Service (NTIS) can be purchased with the NTIS order form provided hereafter.

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<u>Current Abstracts: Photovoltaic Energy, Electricity from Sunlight.</u> Prepared by the Office of Scientific and Technical Information for the Office of Conservation and Renewable Energy, U. S. Department of Energy. Nov.-Dec. 1989, PB89-933006. Available from the Office of Scientific and Technical Information, P.O. Box 62, Oak Ridge, TN 37831.

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Ullal, H. S.; Zweibel, K.; Mitchell, R. L. (November 1989). <u>U.S. Polycrystalline Thin Film Solar Cell Program</u>. SERI/TP-211-3595. 6 pp. Prepared for the Materials Research Society 1989 Fall Meeting, 27 November - 2 December 1989, Boston, Massachusetts. Available NTIS: Order No. DE89009506.

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Zweibel, K. (May 1989). <u>Thin Film Photovoltaics</u>. SERI/TP-211-3501. 7 pp. Prepared for the 24th Intersociety Energy Conversion Engineering Conference, Washington, D.C., 6-11 August 1989. Available NTIS: Order No. DE89009425.

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